TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74HC42AP, TC74HC42AF, TC74HC42AFN

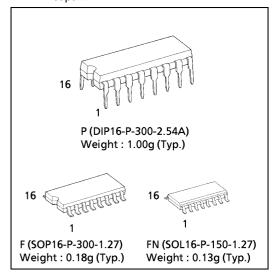
BCD - TO - DECIMAL DECODER

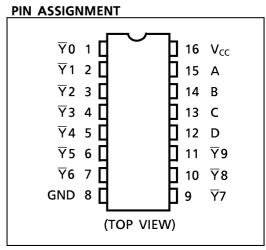
The TC74HC42A is a high speed CMOS BCD-to-DECIMAL DECODER fabricated with silicon gate C^2MOS technology. It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. A BCD code applied to the four inputs (A-D) sets a low level at one of ten decoded outputs. A illegal BCD code such as eleven thru fifteen sets all outputs high. This device can be used as 3-to-8 LINE DECODER when input D is held low. This device is useful for code conversion, address decoding, memory selection, multiplexing, or readout decoding. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

FEATURES:

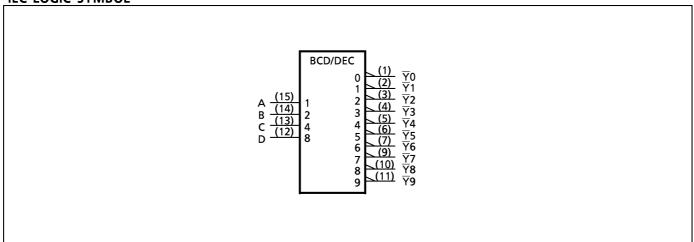
- High Speed······ t_{pd} = 13ns (typ.) at V_{CC} = 5V
- Low Power Dissipation ··············· $I_{CC} = 4\mu A(max.)$ at $Ta = 25^{\circ}C$
- High Noise Immunity $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min.)
- Output Drive Capability 10 LSTTL Loads
- Symmetrical Output Impedance… | I_{OH} | = I_{OL} = 4mA (min.)
- Balanced Propagation Delays $\cdots t_{pLH} \simeq t_{pHL}$
- Wide Operating Voltage Range.... V_{CC} (opr.) = 2V~6V
- Pin and Function Compatible with 74LS42

(Note) The JEDEC SOP (FN) is not available in Japan.





IEC LOGIC SYMBOL

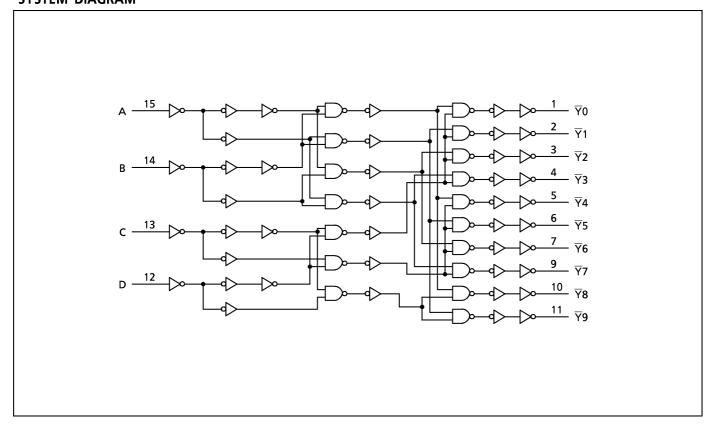


TRUTH TABLE

CODE		BCD II	NPUTS			DECIMAL OUTPUTS								
No.	D	С	В	Α	<u></u> 70	<u></u> 71	₹2	∀ 3	∀ 4	∀ 5	∀ 6	<u>7</u> 7	<u>7</u> 8	∀ 9
0	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н
1	L	L	L	н	Н	L	Н	Н	Н	Н	Н	Н	Н	Н
2	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н	Н	Н
3	L	L	Н	н	Н	Н	Н	L	Н	Н	Н	Н	Н	Н
4	L	н	L	L	Н	Н	Н	Н	L	Н	Н	Н	Н	Н
5	L	н	L	н	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
6	L	н	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н	Н
7	L	н	Н	н	Н	Н	Н	Н	Н	Н	Н	L	Н	Н
8	Н	L	L	L	Н	Н	Н	Н	Н	Н	Н	Н	L	Н
9	Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L
_	Н	Х	Н	Х	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н
	Н	Н	Х	Х	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н

X; Don't Care

SYSTEM DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V _{cc}	− 0.5~7	V
DC Input Voltage	V _{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC Output Voltage	V _{OUT}	−0.5~V _{CC} + 0.5	V
Input Diode Current	I _{IK}	± 20	mA
Output Diode Current	I _{OK}	± 20	mA
DC Output Current	I _{OUT}	± 25	mA
DC V _{CC} / Ground Current	I _{cc}	± 50	mA
Power Dissipation	P _D	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	T _{stg}	−65~150	°C

^{*500}mW in the range of Ta= $-40^{\circ}\text{C}\sim65^{\circ}\text{C}$. From Ta= 65°C to 85°C a derating factor of $-10\text{mW}/^{\circ}\text{C}$ shall be applied until 300mW.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V _{CC}	2~6	\ \
Input Voltage	V _{IN}	0~V _{cc}	V
Output Voltage	V _{OUT}	0~V _{cc}	V
Operating Temperature	T _{opr}	−40~85	°C
Input Rise and Fall Time	t _r , t _f	$0 \sim 1000 (V_{CC} = 2.0V)$ $0 \sim 500 (V_{CC} = 4.5V)$ $0 \sim 400 (V_{CC} = 6.0V)$	ns

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CO	NDITION	V _{CC}	Ta = 25°C			Ta = −40~85°C		UNIT
FARAIVIETER	STIVIBUL	1231 CO	(V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT	
High - Level Input Voltage				2.0 4.5 6.0	1.50 3.15 4.20	_ _ _	_ _ _	1.50 3.15 4.20		V
Low - Level Input Voltage	VIL			2.0 4.5 6.0	_ _ _	_ _ _	0.50 1.35 1.80	_ _ _	0.50 1.35 1.80	V
High - Level Output Voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	$I_{OH} = -20\mu A$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	_ _ _	1.9 4.4 5.9	_ _ _	v
Output Voltage			$I_{OH} = -4 \text{ mA}$ $I_{OH} = -5.2 \text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	_	4.13 5.63	_	
Low - Level Output Voltage	V _{OL}	V _{IN} =	I _{OL} = 20μΑ	2.0 4.5 6.0	_ _ _	0.0 0.0 0.0	0.1 0.1 0.1	_ _ _	0.1 0.1 0.1	V
Output voltage		V _{IH} or V _{IL}	$I_{OL} = 4 mA$ $I_{OL} = 5.2 mA$	4.5 6.0	_ _	0.17 0.18	0.26 0.26	_ _	0.33 0.33	
Input Leakage Current	I _{IN}	$V_{IN} = V_{CC}$ or GND		6.0	_	_	± 0.1	_	± 1.0	
Quiescent Supply Current	I _{cc}	$V_{IN} = V_{CC}$ or GND		6.0	_	_	4.0	_	40.0	μ A

AC ELECTRICAL CHARACTERISTICS ($C_L = 15pF$, $V_{CC} = 5V$, $Ta = 25^{\circ}C$, Input $t_r = t_f = 6ns$)

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PARAMETER	SYMBOL	MBOL TEST CONDITION		TYP.	MAX.	UNIT
Output Transition Time	t _{TLH} t _{THL}		_	4	8	ns
Propagation Delay Time	t _{pLH} t _{pHL}		_	13	25	113

AC ELECTRICAL CHARACTERISTICS ($C_L = 50pF$, Input $t_r = t_f = 6ns$)

PARAMETER	SYMBOL	TEST CONDITION .		Ta = 25°C			Ta = -4	UNIT	
PARAIVIETER	STIVIBUL	TEST CONDITION	$V_{CC}(V)$	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
	t _{TLH}		2.0	_	30	75	_	95	
Output Transition Time	l .		4.5	_	8	15	_	19	
·	t _{THL}		6.0	-	7	13	_	16	ns
	+		2.0	_	48	145	_	180	'''
Propagation Delay Time	t _{pLH}		4.5	_	16	29	_	36	
,	t _{pHL}		6.0	_	14	25	_	31	
Input Capacitance	C _{IN}			-	5	10	_	10	2
Power Dissipation Capacitance	C _{PD} (1)			_	68	_	_	_	pF

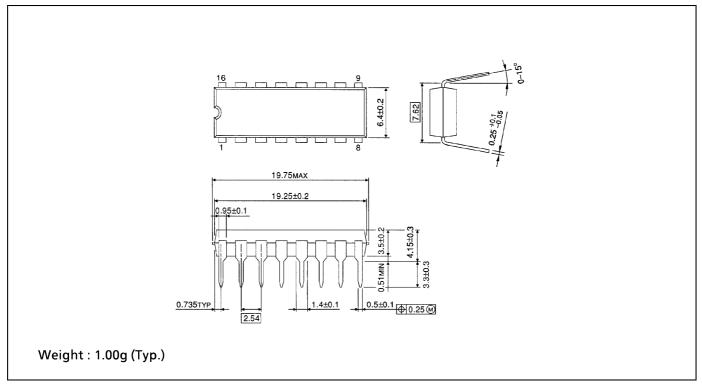
Note (1) C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

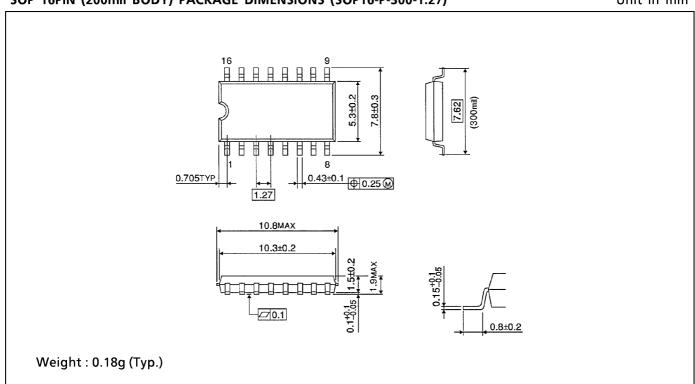
DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

Unit in mm



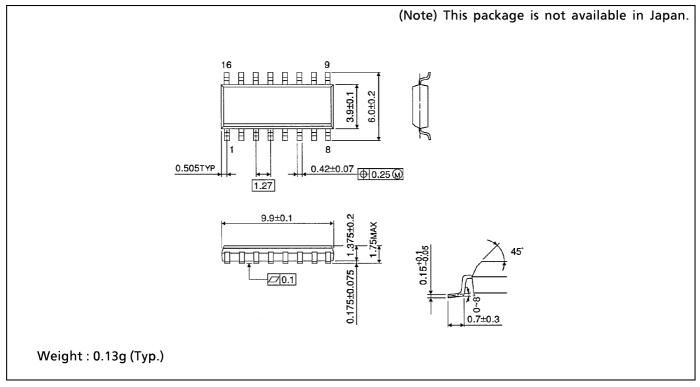
SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

Unit in mm



SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)

Unit in mm



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